

<b>Notice of References Cited</b>	Application/Control No. 10/632,665		Applicant(s)/Patent Under Reexamination HAPARNAS ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0130627	06-2005	Calmels et al.	455/411
*	B	US-2006/0148402	07-2006	Hagiwara, Toyotaka	455/041.1
*	C	US-2002/0126845	09-2002	Hue et al.	380/247
*	D	US-2004/0203354	10-2004	Yue, Lin	455/041.1
*	E	US-2004/0203372	10-2004	Morimoto, Hiroyuki	455/041.2
*	F	US-2004/0203950	10-2004	Chen, James	455/466
*	G	US-2004/0203384	10-2004	Sugikawa et al.	455/041.2
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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